

Notice of References Cited

Application/Control No.

09/846,939

Applicant(s)/Patent Under

Reexamination

CHENG ET AL.

Examiner

Carlene Gordon

Art Unit

2124

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,434,503	08-2002	Sommer, Michael Bernhard	702/123
	B	US-5,845,234	12-1998	Testa et al.	702/119
	C	US-6,574,760	06-2003	Mydill, Marc	714/724
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Toner et al., "A BIST Scheme for a SNR, Gain Trackin, and Frequency Response Test of a Sigma-Delta ADC", January 1995, IEEE Transactions on Circuits and Systems-II: Analog and Digital Signal Processing, Vol. 42, No. 1, pg. 1
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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